

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	67	pseudorange and epoch\$ and data adj bits	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 10:46
L2	7	(US-20040172195-\$).did. or (US-6819707-\$ or US-6768451-\$ or US-6714158-\$ or US-6704348-\$ or US-6606346-\$ or US-6546040-\$). did.	US-PGPUB; USPAT	OR	OFF	2005/03/14 11:55
L3	2	("6628234").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/03/14 11:55
L4	80	("4241411" "5043736" "5271034" "5276496" "5355222" "5387993" "5388147" "5394155" "5457729" "5477458" "5479482" "5525999" "5548637" "5555286" "5572195" "5587716" "5606736" "5638379" "5646519" "5654717" "5659596" "5663734" "5686925" "5689238" "5689271" "5691726" "5734966" "5740538" "5751777" "5764704" "5781156" "5812087" "5825327" "5828670" "5831574" "5831577" "5832375" "5841396" "5854608" "5859621" "5873048" "5874914" "5884214" "5890068" "5897605" "5899957" "5900838" "5901171" "5909640" "5913170" "5917383" "5918181" "5929752" "5943381" "5945944" "5945963" "5963180" "5999124" "6002363" "6014109" "6016119" "6041280" "6044257" "6052081" "6061018" "6064336" "6100806" "6104340" "6127945" "6191730" "6205377" "6226510" "6236354" "6297771" "6298229" "6327534" "6331836" "6334061" "RE36530" "RE36791").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/03/14 12:35

L5	22	((("5387993") or ("5912644") or ("5926745") or ("6040798") or ("6498585") or ("6515620") or ("6529160") or ("6628234") or ("6144336") or ("6285316") or ("6295023"))).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:47
L6	1	wo-9834128-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:52
L7	1	ca-2260762-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:54
L8	2	wo-9802973-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:47
L9	2	wo-9853573-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:48
L10	2	wo-9953338-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:48
L11	2	wo-9956144-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:48
L12	2	wo-9956145-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:48
L13	2	ep-1014107-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:48
L14	13	6 or 7 or 8 or 9 or 10 or 11 or 12 or 13	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:49
L15	0	jp-40526714-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:54
L16	0	jp-4526714-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:54
L17	2	gb-2292257-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:55
L18	2	wo-9714054-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:55
L19	2	wo-9714056-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:55
L20	1	wo-9721109-\$.did.	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:58
L21	7	17 or 18 or 19 or 20	EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:56
L22	878	(342/357.12).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/03/14 12:59
L23	429	(342/357.12).CCLS.	US-PGPUB; USPAT	OR	OFF	2005/03/14 13:40

L24	15	data adj bits and stacks and epochs	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 13:59
L25	73	pseudonoise and synchroniz\$ and epoch\$	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 14:11
L26	488	spread adj spectrum and synchroniz\$ and epoch\$	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 14:14
L27	369	26 and (pair\$2 or group\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 14:15
L28	333	27 and (align\$ or correlat\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 14:16
L29	5	28 and stacks	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 14:17
L30	219	28 and (sum\$1 or add\$1) and (difference\$1 or subtract\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 14:18
L31	70	30 and pseudorange\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/14 14:18
L32	19	(US-20040172195-\$ or US-20030088741-\$).did. or (US-6819707-\$ or US-6768451-\$ or US-6714158-\$ or US-6704348-\$ or US-6606346-\$ or US-6546040-\$ or US-5890068-\$ or US-5901171-\$ or US-6295023-\$ or US-6847676-\$ or US-6346911-\$ or US-6329946-\$ or US-5867525-\$ or US-6850557-\$ or US-6289041-\$ or US-5373531-\$). did. or (GB-2321833-\$).did.	US-PGPUB; USPAT; DERWENT	OR	OFF	2005/03/14 14:24
L33	4	("5579338" "6181911" "6346911" "6459407").PN. OR ("6768451").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/03/14 14:37
L34	7	(US-20030088741-\$).did. or (US-6606346-\$ or US-6295023-\$ or US-6847676-\$ or US-6850557-\$ or US-6289041-\$ or US-5373531-\$). did.	US-PGPUB; USPAT	OR	OFF	2005/03/14 14:48

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Rezeanu, S.-C.; Ziemer, R.E.;

Communications Letters, IEEE , Volume: 2 , Issue: 2 , Feb. 1998

Pages:33 - 35

[\[Abstract\]](#) [\[PDF Full-Text \(96 KB\)\]](#) **IEEE JNL**
2 Joint maximum-likelihood parameter estimation for burst DS spread spectrum transmission
Rezeanu, S.-C.; Ziemer, R.E.; Wickert, M.A.;

Communications, IEEE Transactions on , Volume: 45 , Issue: 2 , Feb. 1997

Pages:227 - 238

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3 A Novel Spread-Spectrum Receiver Synchronization Scheme Using a SAW-Tapped Delay Line
Baier, P.; Dostert, K.; Pandit, M.;

Communications, IEEE Transactions on [legacy, pre - 1988] , Volume: 30 , Issue: 5 , May 1982

Pages:1037 - 1047

[\[Abstract\]](#) [\[PDF Full-Text \(1000 KB\)\]](#) **IEEE JNL**
4 Performance Analysis for the Expanding Search PN Acquisition Algorithm
Braun, W.;

Communications, IEEE Transactions on [legacy, pre - 1988] , Volume: 30 , Issue: 3 , Mar 1982

Pages:424 - 435

[\[Abstract\]](#) [\[PDF Full-Text \(648 KB\)\]](#) IEEE JNL

5 Signal recognition and signature code acquisition in CDMA mobile communications

De Gaudenzi, R.; Giannetti, F.; Luise, M.;

Vehicular Technology, IEEE Transactions on , Volume: 47 , Issue: 1 , Feb. 1996
Pages:196 - 208

[\[Abstract\]](#) [\[PDF Full-Text \(488 KB\)\]](#) IEEE JNL

6 Joint maximum-likelihood data and bit synchronization epoch estimation for burst direct sequence spread-spectrum transmission

Rezeanu, S.-C.; Ziemer, R.E.;

Military Communications Conference, 1996. MILCOM '96, Conference Proceedings, IEEE , Volume: 3 , 21-24 Oct. 1996
Pages:801 - 805 vol.3

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7 User recognition and signature code acquisition for CDMA receivers

De Gaudenzi, R.; Giannetti, F.; Luise, M.;

Communications, 1995. ICC 95 Seattle, Gateway to Globalization, 1995 IEEE International Conference on , Volume: 3 , 18-22 June 1995
Pages:1592 - 1596 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(452 KB\)\]](#) IEEE CNF

8 A comparison of multiple-dwell cell testing strategies in serial search direct sequence spread spectrum code acquisition

Eynon, A.J.; Tozer, T.C.;

Military Communications Conference, 1995. MILCOM '95, Conference Record, IEEE , Volume: 1 , 5-8 Nov. 1995
Pages:357 - 361 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(420 KB\)\]](#) IEEE CNF

9 Performance of sequential detectors for the acquisition of data modulated spread spectrum pseudo noise signals

Ravi, K.V.; Ormondroyd, R.F.;

Communications, 1991. ICC 91, Conference Record. IEEE International Conference on , 23-26 June 1991
Pages:575 - 579 vol.2

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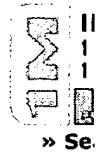
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Ray, G.C.; Kaplan, A.Ya.; Jovanov, E.;

 Engineering in Medicine and Biology society, 1997. Proceedings of the 19th Annual International Conference of the IEEE, Volume: 1, 30 Oct.-2 Nov. 1997
 Pages:227 - 230

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2 Partial discharge pulse epoch distribution in dielectric liquids and impregnated papers under AC conditions
Pompili, M.; Mazzetti, C.; Bartnikas, R.;

 Dielectric Liquids, 1999. (ICDL '99) Proceedings of the 1999 IEEE 13th International Conference on, 20-25 July 1999
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3 Automatic seizure detection in newborns and infants
Gotman, J.; Zhang, J.; Rosenblatt, B.; Gottesman, R.;

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 Pages:913 - 914 vol.2

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4 Automated detection and elimination of periodic ECG artifacts in EEG using the energy interval histogram method
Hae-Jeong Park; Do-Un Jeong; Kwang-Suk Park;

Biomedical Engineering, IEEE Transactions on, Volume: 49, Issue: 12, Dec.